

<b>Notice of References Cited</b>	Application/Control No. 10/507,258		Applicant(s)/Patent Under Reexamination PEZZOTTI, GIUSEPPE	
	Examiner BOBBY RAMDHANIE		Art Unit 1797	Page 1 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0017059	08-2001	Xu et al.	73/800
*	B	US-5,278,408	01-1994	Kakibayashi et al.	250/311
*	C	US-4,774,150	09-1988	Amano et al.	428/690
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Galiotis, C.; Paipetis, A.; Marston, C. "Unification of Fibre/Matrix Interfacial Measurements with Ramam Microscopy." J. Raman Spectrosc., 1999, 30, pp. 899-912.
	V	Pezzotti, G. "In situ Study of Fracture Mechanisms in Advanced Ceramics using Fluorescence and Raman Microprobe Spectroscopy." J. Raman Spectrosc. 1999, 30, pp. 867-875.
	W	Schlichting, K. W.; Vaidyanathan, K. Sohn, Y.H.; Jordan, E.H.; Gell, M.; Padture, N.P. "Application of Cr <sup>3+</sup> photoluminescence piezo-spectroscopy to plasma-sprayed thermal barrier coatings for residual stress measurement." Materials Science and Engineering A 291, 2000. pp. 68-77.
	X	Muraki, K.G.; Sergo, V.; Pezzotti, G.; Nishida, T. "Mapping of residual stresses around an indentation in b-Si <sub>3</sub> N <sub>4</sub> using Raman Spectroscopy." Journal of Materials Science, 1997, pp. 5419-5423.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	H	US-			
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yoshikawa, M.; Maegawa, M.; Katagiri, G.; Ishida, H. "Characterization of anisotropic stress around Si trenches by polarized Raman spectroscopy." J. Appl. Phys. 78 (2), 1995. pp. 941-944.
	V	Muraki, N.; Matoba, N.; Hirano, T.; Yoshikawa, M. "Determination of thermal stress distribution in a model microelectronic device encapsulated with alumina filled epoxy resin using fluorescence spectroscopy." Polymer, 43, 2002, pp. 1277-1285.
	W	
	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.